TOSHIBA POWER TRANSISTOR MODULE SILICON PNP TRIPLE DIFFUSED TYPE (DARLINGTON POWER TRANSISTOR 4 IN 1)

MP4508

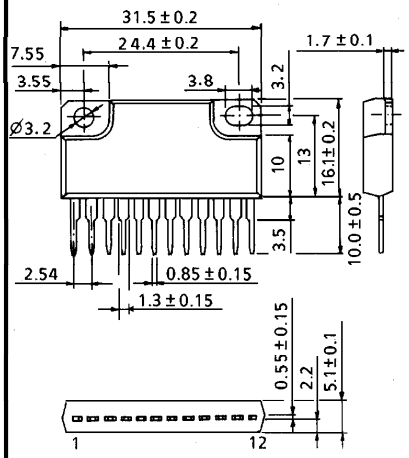
HIGH POWER SWITCHING APPLICATIONS.

HAMMER DRIVE, PULSE MOTOR DRIVE AND INDUCTIVE LOAD SWITCHING.

INDUSTRIAL APPLICATIONS

- Package with Heat Sink Isolated to Lead (SIP 12 Pin)
- High Collector Power Dissipation (4 Devices Operation) : $P_T = 5W$ (Ta = 25°C)
- High Collector Current : $I_{C\,(DC)} = -5A$ (Max.)
- High DC Current Gain : $h_{FE} = 1000$ (Min.) ($V_{CE} = -3V$, $I_C = -3A$)

Unit in mm



1, 5, 8, 12	BASE
2, 4, 9, 11	COLLECTOR
3, 6, 7, 10	EMITTER

JEDEC	—
EIAJ	—
TOSHIBA	2-32B1B

Weight : 6.0g

MAXIMUM RATINGS (Ta = 25°C)

CHARACTERISTIC		SYMBOL	RATING	UNIT
Collector-Base Voltage		V_{CBO}	−100	V
Collector-Emitter Voltage		V_{CEO}	−100	V
Emitter-Base Voltage		V_{EBO}	−5	V
Collector Current	DC	I_C	−5	A
	Pulse	I_{CP}	−8	
Continuous Base Current		I_B	−0.1	A
Collector Power Dissipation (1 Device Operation)		P_C	3.0	W
Collector Power Dissipation (4 Devices Operation)	Ta = 25°C	P_T	5.0	W
	Tc = 25°C		25	
Isolation Voltage		V_{Isol}	1000	V
Junction Temperature		T_j	150	°C
Storage Temperature Range		T_{stg}	−55~150	°C

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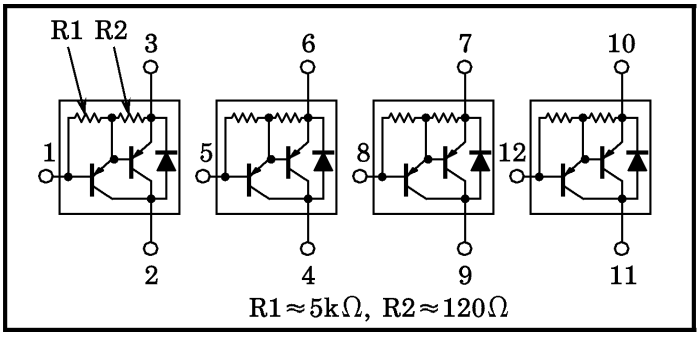
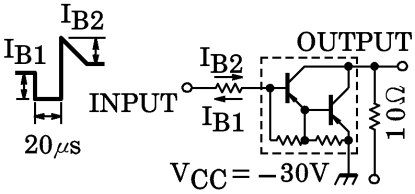
ARRAY CONFIGURATION



THERMAL CHARACTERISTICS

CHARACTERISTIC	SYMBOL	MAX.	UNIT
Thermal Resistance of Junction to Ambient (4 Devices Operation, Ta = 25°C)	$\Sigma R_{th\ (j\text{-}a)}$	25	°C / W
Thermal Resistance of Junction to Case (4 Devices Operation, Tc = 25°C)	$\Sigma R_{th\ (j\text{-}c)}$	5.0	°C / W
Maximum Lead Temperature for Soldering Purposes (3.2mm from Case for 10s)	T_L	260	°C

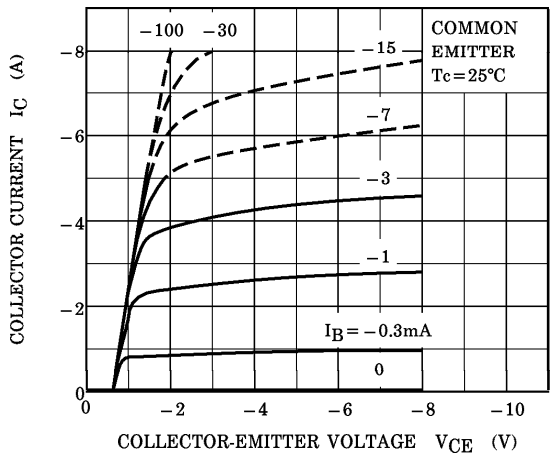
ELECTRICAL CHARACTERISTICS (Ta = 25°C)

CHARACTERISTIC		SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Collector Cut-off Current		I_{CBO}	$V_{CB} = -100V$, $I_E = 0$	—	—	−10	μA
Collector Cut-off Current		I_{CEO}	$V_{CE} = -100V$, $I_B = 0$	—	—	−10	μA
Emitter Cut-off Current		I_{EBO}	$V_{EB} = -5V$, $I_C = 0$	−0.3	—	−2.0	mA
Collector-Base Breakdown Voltage		$V_{(BR)\ CBO}$	$I_C = -1mA$, $I_E = 0$	−100	—	—	V
Collector-Emitter Breakdown Voltage		$V_{(BR)\ CEO}$	$I_C = -30mA$, $I_B = 0$	−100	—	—	V
DC Current Gain		$h_{FE\ (1)}$	$V_{CE} = -3V$, $I_C = -0.5A$	1000	—	—	
		$h_{FE\ (2)}$	$V_{CE} = -3V$, $I_C = -3A$	1000	—	—	
Saturation Voltage	Collector-Emitter	$V_{CE\ (sat)}$	$I_C = -3A$, $I_B = -12mA$	—	—	−2.0	V
	Base-Emitter	$V_{BE\ (sat)}$	$I_C = -3A$, $I_B = -12mA$	—	—	−2.5	
Transition Frequency		f_T	$V_{CE} = -3V$, $I_C = -0.5A$	3	—	—	MHz
Collector Output Capacitance		C_{ob}	$V_{CB} = -50V$, $I_E = 0$, f = 1MHz	—	40	—	pF
Switching Time	Turn-on Time	t_{on}		—	0.5	—	μs
	Storage Time	t_{stg}		—	3.0	—	
	Fall Time	t_f	$-I_{B1} = I_{B2} = 12mA$, DUTY CYCLE ≦ 1%	—	2.0	—	

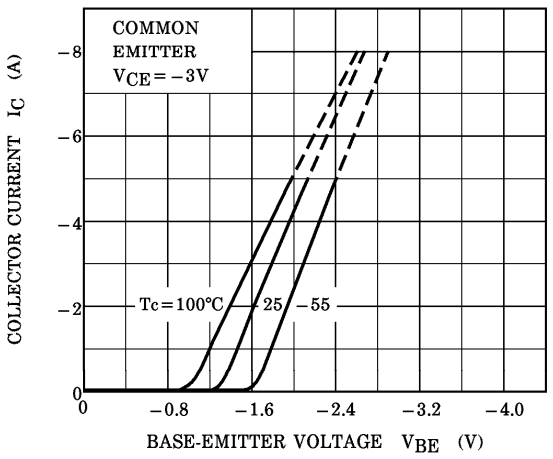
EMITTER-COLLECTOR DIODE RATINGS AND CHARACTERISTICS (Ta = 25°C)

CHARACTERISTIC	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Forward Current	I_{FM}	—	—	—	5	A
Surge Current	I_{FSM}	t = 1s, 1 shot	—	—	8	A
Forward Voltage	V_F	I_F = 1A, I_B = 0	—	—	2.0	V
Reverse Recovery Time	t_{rr}	I_F = 5A, V_{BE} = 3V, dI_F/dt = 50A/μs	—	1.0	—	μs
Reverse Recovery Charge	Qrr		—	8	—	μC

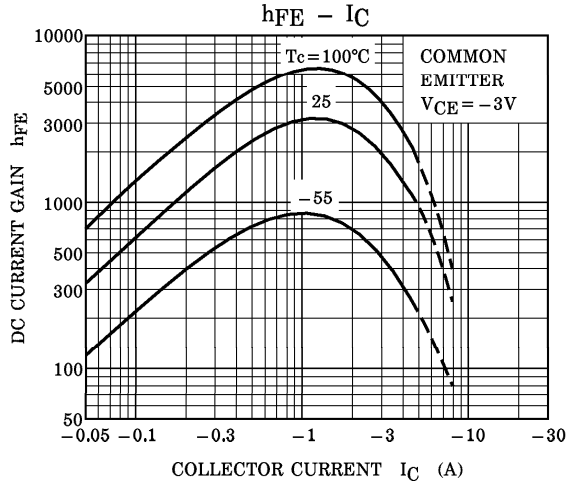
I_C – V_{CE}



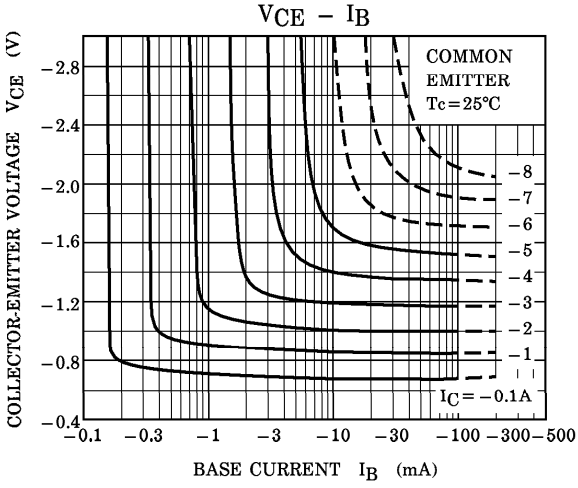
I_C – V_{BE}



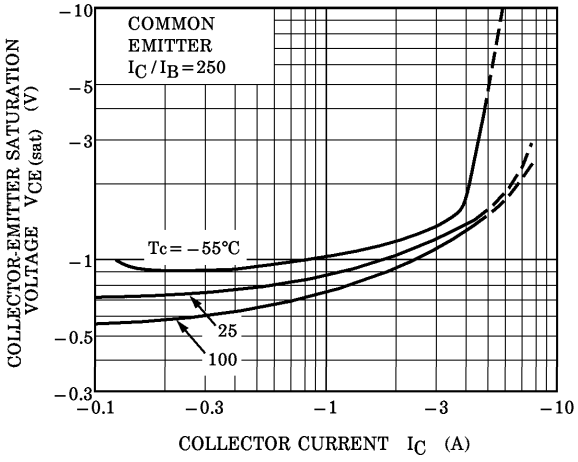
h_{FE} – I_C



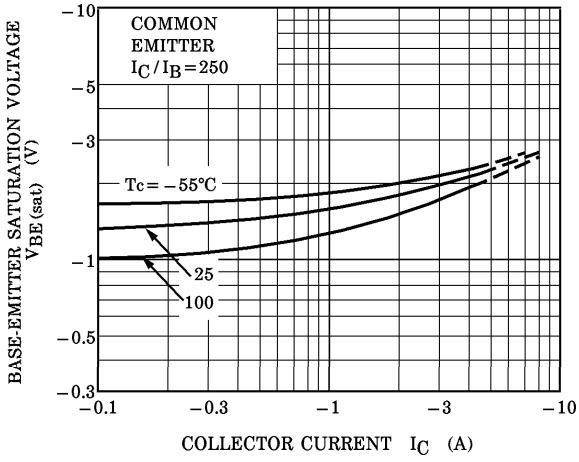
V_{CE} – I_B



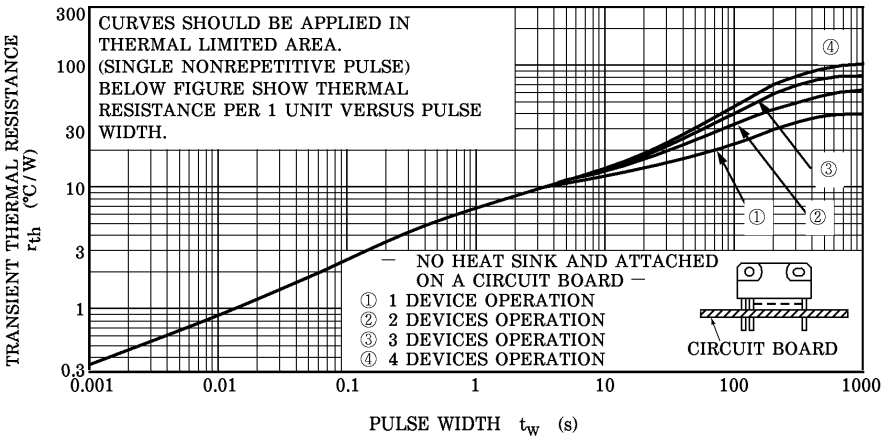
$V_{CE\,(sat)}$ – I_C



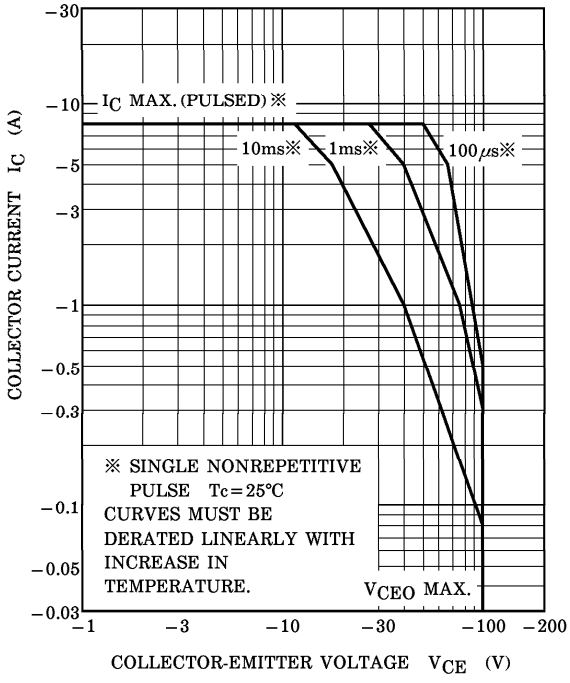
$V_{BE\,(sat)}$ – I_C



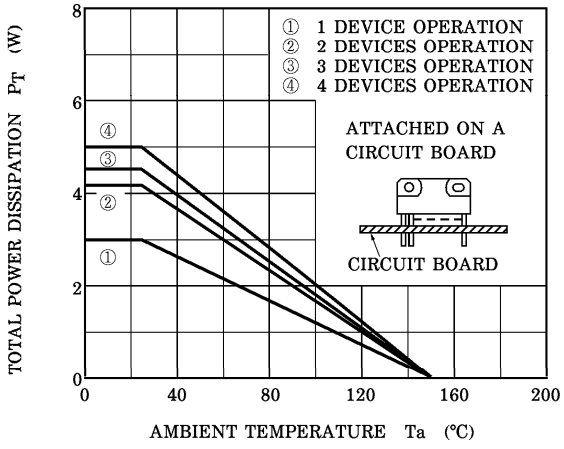
$r_{th} - t_w$



SAFE OPERATING AREA



$P_T - Ta$



$\Delta T_j - P_T$